PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of

Docket No: Q81522

Munetaka WATANABE, et al.

Appln. No.: 10/593,288

Group Art Unit: 2814

Confirmation No.: 8457

Examiner: Bilkis Jahan

Filed: September 18, 2006

For: TRANSPA

TRANSPARENT POSITIVE ELECTRODE

DECLARATION UNDER 37 C.F.R. § 1.132

Mail Stop Amendment Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

I, Munetaka WATANABE, hereby declare and state:

THAT I am a citizen of Japan;

THAT I have received the degree of Master of Engineering in 1992 from Seikei university in

Tokyo, Japan;

THAT I have been employed by SHOWA DENKO K.K. since April 1, 1992, where I hold a position as a researcher, with responsibility for research and development of LED devices;

THAT I am one of the inventors of the subject matter described and claimed in the above-identified application, and that I am familiar with the Office Action dated September 21, 2009 where U.S. Patent No. 6,331,450 to Uemura was cited as disclosing a contact metal layer having a thickness of about $0.3 \,\mu\text{m}$.

The following experiments were carried out, either by me or under my direct supervision.

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The transmittance of two Pt film samples with a thickness of 7.5 nm and 311 nm (i.e., a

thickness of about 0.3 μ m), respectively, were investigated and tested.

Experimental procedure

The Pt film was deposited on a glass substrate by sputtering, and the transmittance of the

resulting Pt film in the visible light region (350 nm to 700 nm) was measured, according to the

following conditions.

Sputtering conditions: pressure 0.4 Pa, DC output 1000 W

Pt film thickness: measured by using DEKTAK manufactured by Veeco

Transmittance: measured by using spectrophotometer UV2450 manufactured by

Shimadzu

Results

The results of the measured transmittances of the two Pt film samples are shown in Table

1 and Figure 1 below.

The Pt film having the thickness of 7.5 nm has a transmittance in the range of 33% to

46%. The Pt film having the thickness of 311 nm has a transmittance in the range of 0.005% to

0.014%. In particular, at the wavelength of 450 nm, i.e., blue light, the Pt film having a

thickness of 7.5 nm has a transmittance of 41.5%, whereas the Pt film having a thickness of 311

nm has a transmittance of 0.014%.

Therefore, these test results demonstrate that a Pt film having a thickness of 7.5 nm is

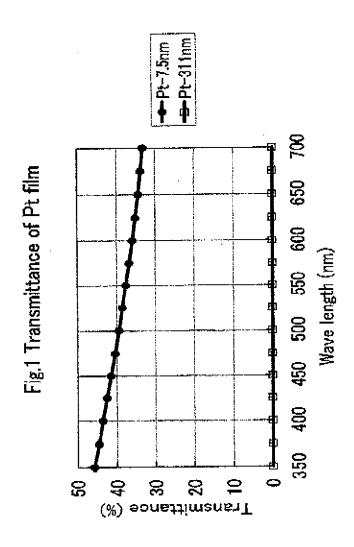
transparent, whereas a Pt film having a thickness of 311 nm is not.

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Table 1 Transmittance (%)

	Wavelength (nm)							
Pt thickness	350	400	450	500	550	600	650	700
7.5 nm	45.8	43.6	41.5	39.4	37.7	35.9	34.4	33.1
311 nm	0.005	0.014	0.014	0-014	0.014	0.012	0.012	0.011



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Discussion

Present claim 12 is directed to a gallium nitride-based compound semiconductor light-

emitting device comprising a transparent positive electrode, including a contact metal layer

having a thickness of from 0.1 to 7.5 nm. The Examiner cited U.S. Patent No. 6,331,450 to

Usemura as disclosing a contact metal layer having a thickness of 0.3 μ m (i.e., 300 nm), and

considered that it would have been obvious to use any suitable thickness for the device.

However, I respectfully disagree. As I show above, the contact metal layer of Uemura having a

thickness of about 0.3 μm does not transmit light, such that there is no apparent reason to reduce

the thickness of the contact metal layer by forty fold (to an upper limit of 7.5 nm) so as to obtain

a transparent contact metal layer having a property opposite that of the opaque contact metal

layer of Uemura.

I declare further that all statements made herein of my own knowledge are true and that

all statements made on information and belief are believed to be true; and further that these

statements were made with the knowledge that willful false statements and the like so made are

punishable by fine or imprisonment, or both, under Section 1001 of Title 18 of the United States

Code, and that such willful false statements may jeopardize the validity of the application or any

patent issuing thereon.

Date: 12/16/2009

Munetaka Watanahe